



Matching Electronic Fingerprints of RFID Tags Using the Hotelling's Algorithm

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Nurbek Saparkhojayev and Dale R. Thompson, Ph.D., P.E.
Computer Science and Computer Engineering Dept.
University of Arkansas

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Problem



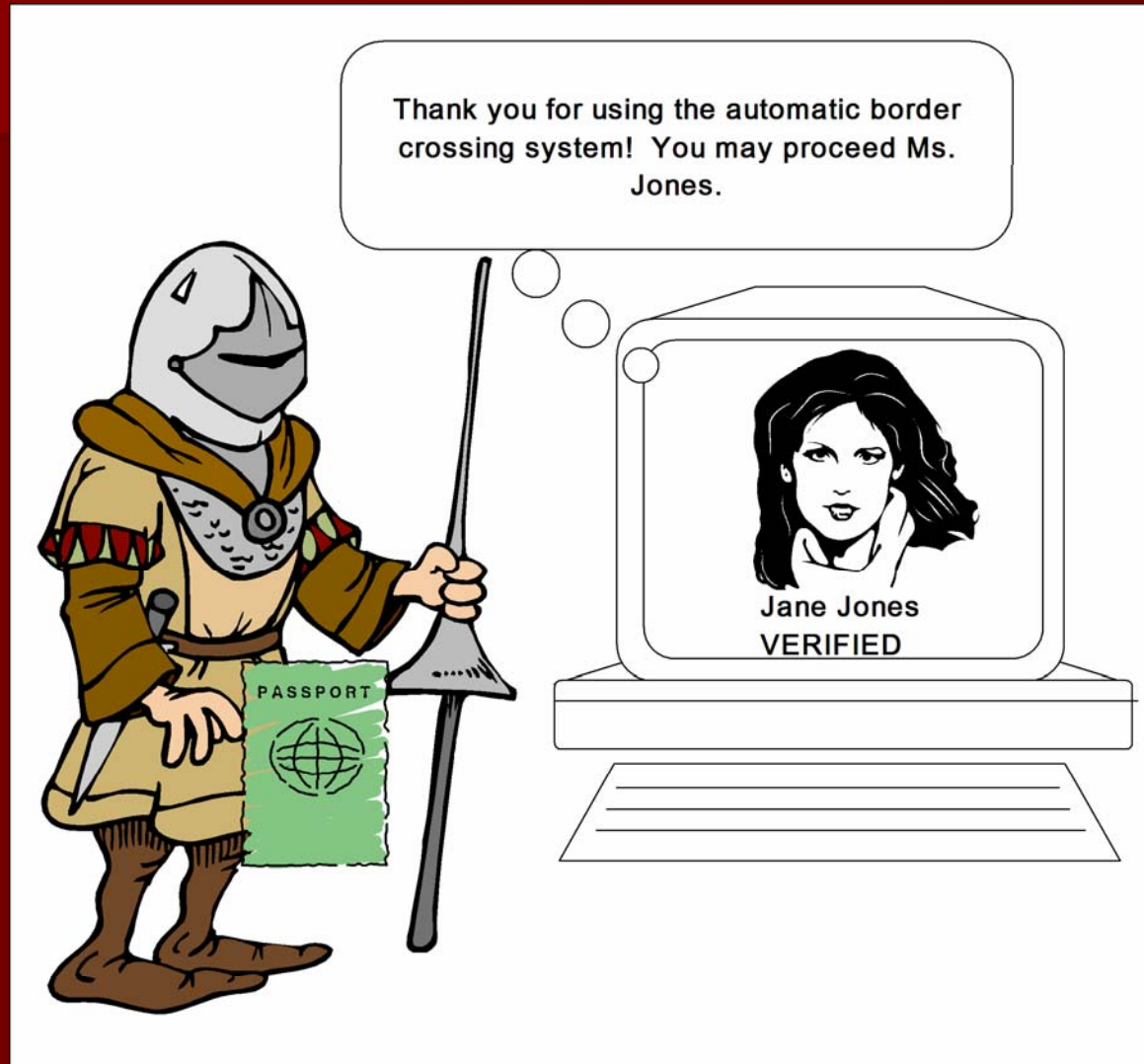
- Counterfeiting travel documents such as ePassport, DHS PASS card, and future drivers licenses
- Travel documents contain radio frequency identification (RFID) tags



Threats to RFID tags

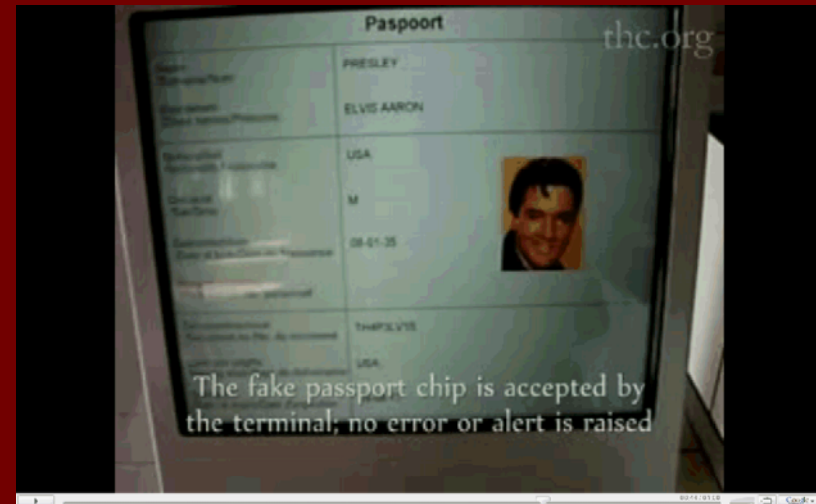
- Cloning the tag
 - Copy contents of tag to another tag
- Side-channel (non-invasive) attacks
 - Monitor certain external parameters such as power consumption, timing delay, or electromagnetic emission
 - Inject noise/faults to the target to cause irregular behaviors

Tag Counterfeiting/Cloning (Spoofing Identity)



Manipulating Data on Passport

- The Hacker's Choice (Oct. 2, 2008)
 - Copied passport
 - Replaced picture with Elvis's picture
 - Turned off active verification
 - Tested on boarding pass machine
 - <http://freeworld.thc.org/thc-epassport/>
 - <http://www.youtube.com/watch?v=4HngStyEm4s>
- Used Jeroen van Beek method presented at Black Hat conference



Counterfeiting Mitigation

- Tag authentication using cryptography
 - Store secrets on the tag that can be verified
 - Secret keys, symmetric key and public key cryptography
- Physical unclonable functions (PUFs)
- Electronic fingerprint (E-Fingerprint)

Objective

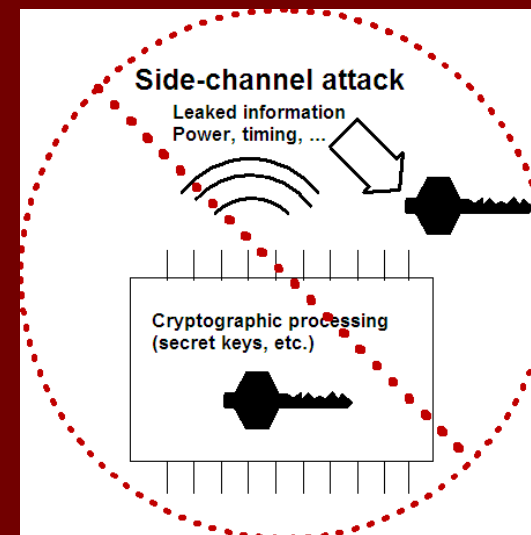
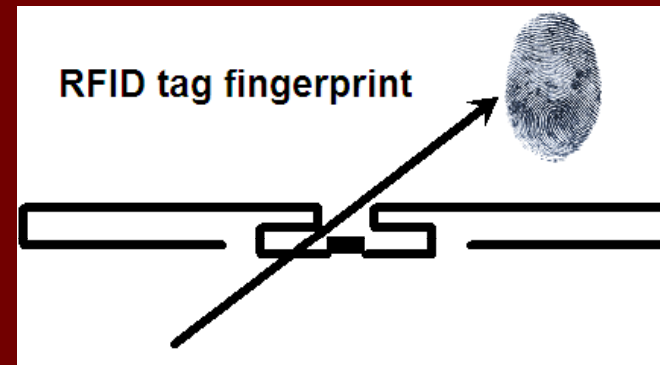
- Prevent counterfeiting of RFID tags
 - Methods for creating electronic fingerprint based on physical characteristics of tag
 - Digital integrated circuit (IC) design methodology that mitigates power- and timing-based side-channel attacks



Approach

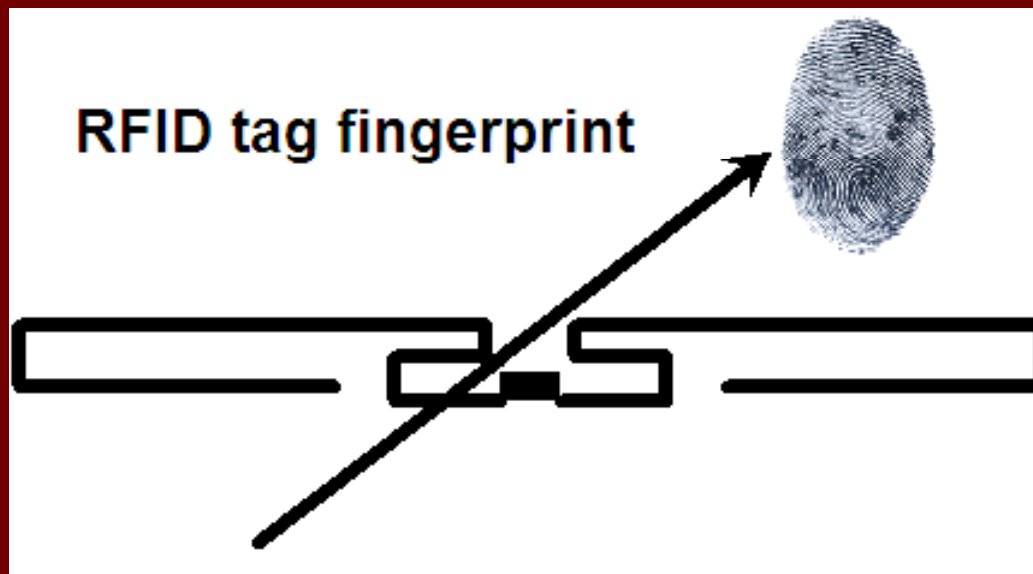


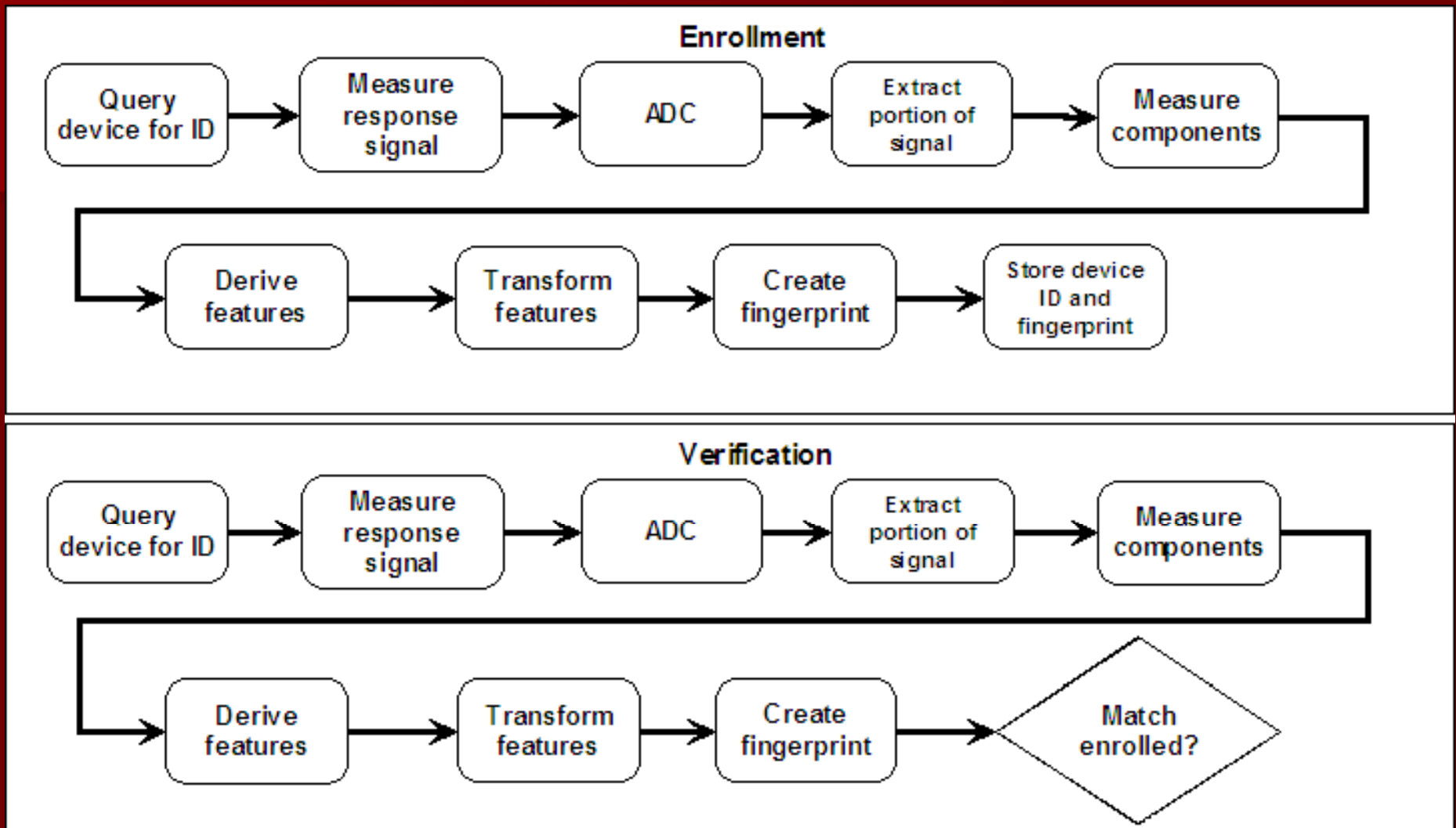
- Electronic fingerprint (e-fingerprint)
 - Authentication becomes a function of what the device “is” in addition to a secret it “knows.”
- Digital integrated circuit (IC) design methodology that mitigates power- and timing-based side-channel attacks



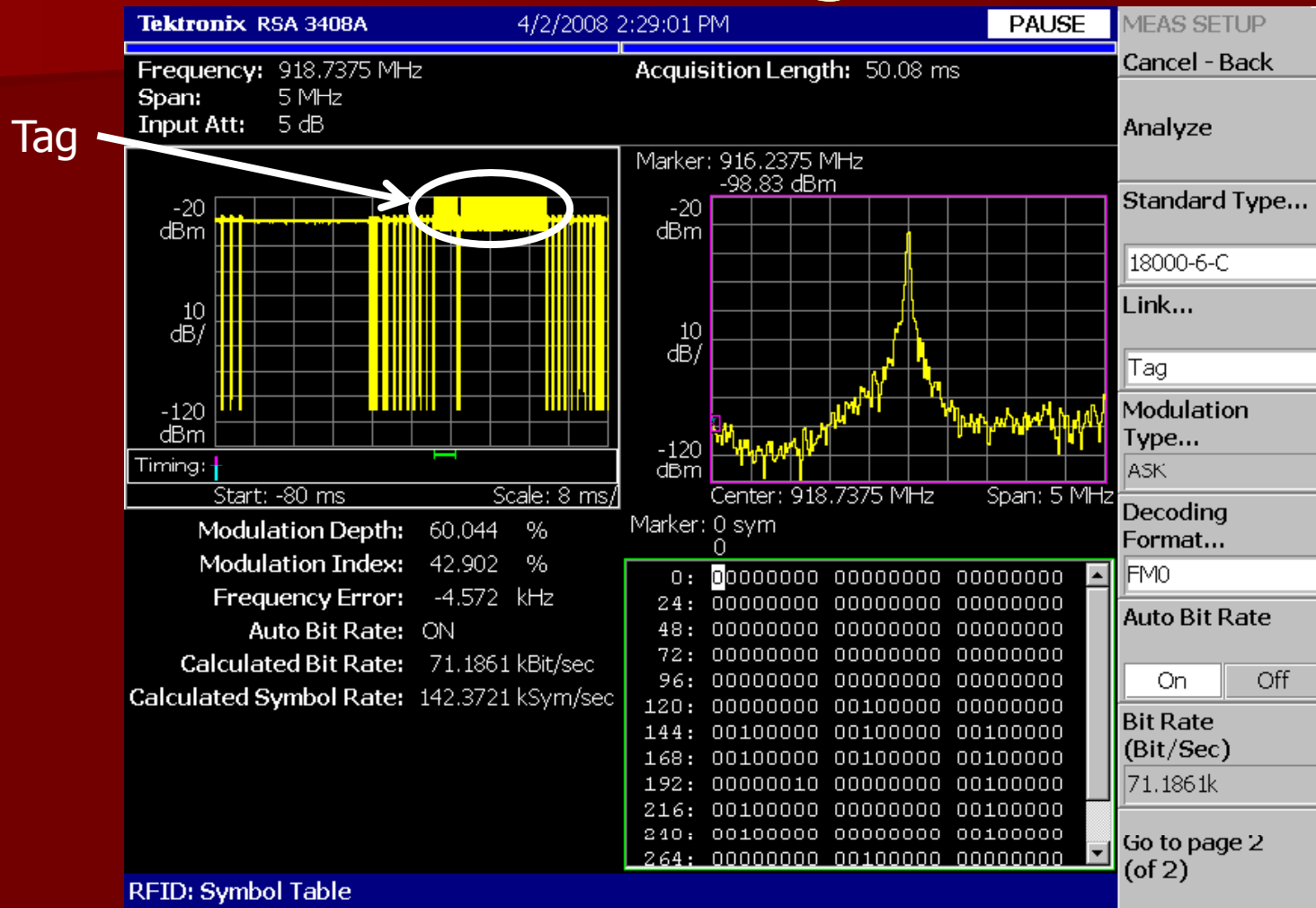
Two-layer security

- Authentication becomes a function of what the device “is” in addition to a secret it “knows.”
- Two-layers
 - Cryptography
 - Electronic fingerprint (E-fingerprint)





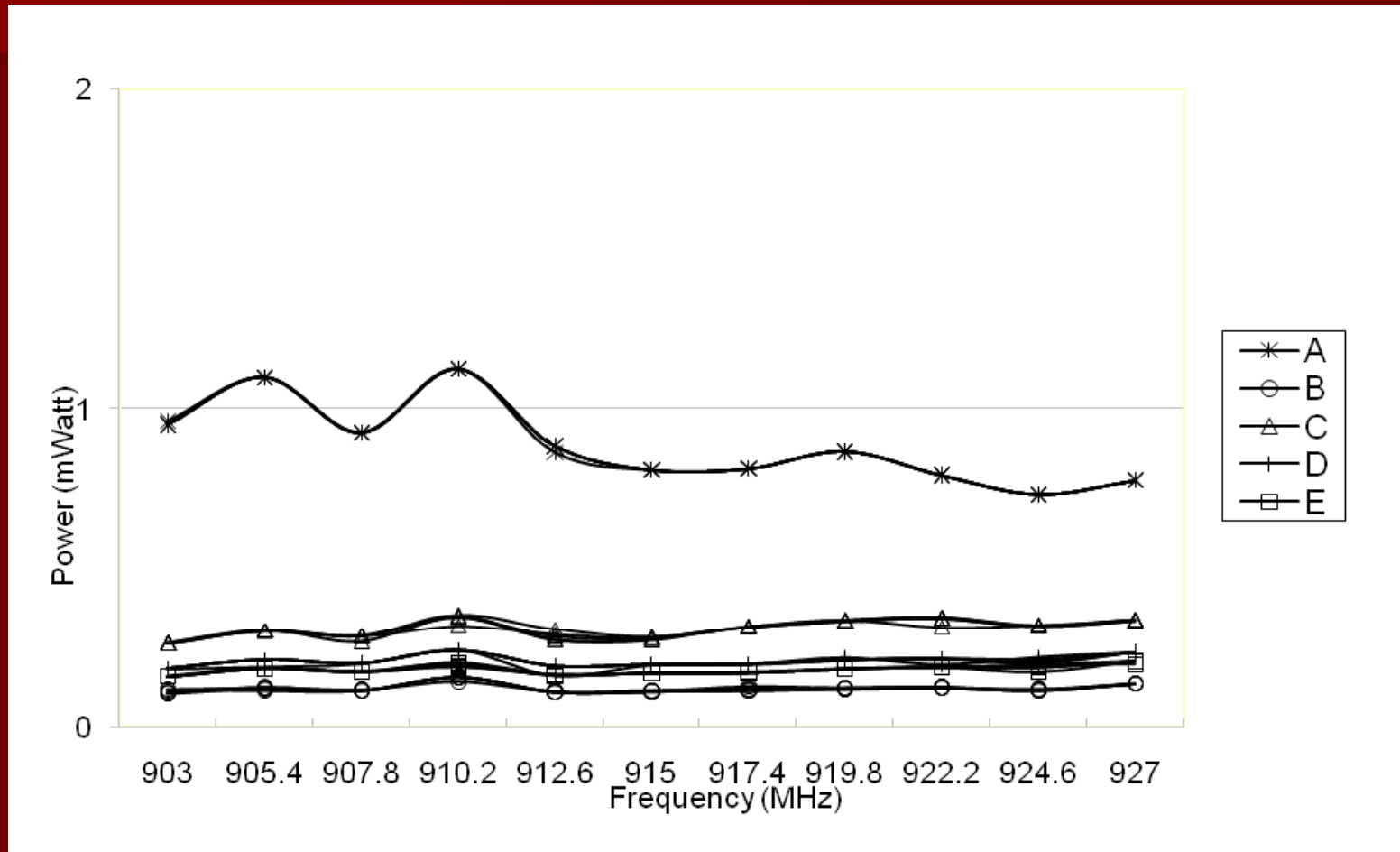
Communication between reader and tag



Features

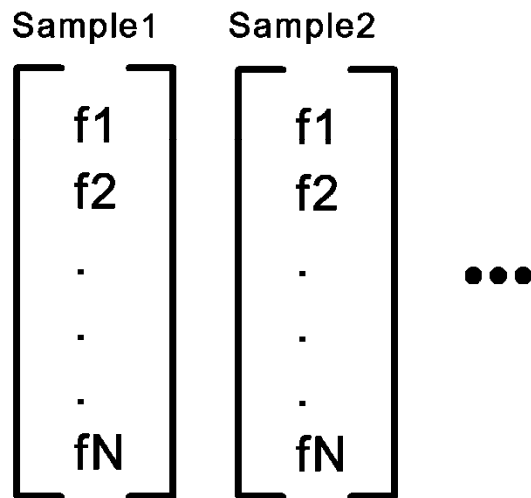
- Minimum power response at multiple frequencies (MPRMF)
- Timing
- Frequency
- Phase
- Transients

Minimum power response measured at multiple frequencies

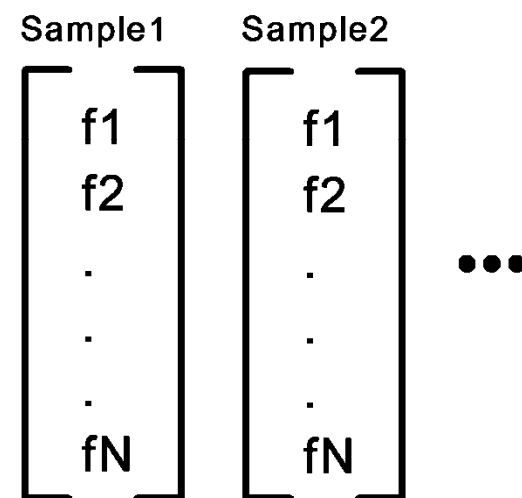


What will the fingerprint look like?

Enrolled fingerprints



Observed fingerprints



FAR and FRR

False acceptance rate (FAR)

- Probability that a false identity claim will be accepted
- Type II error
- **Like biometrics, most serious type of error**

False rejection rate (FRR)

- Probability that a true identity claim is falsely rejected
- Type I error

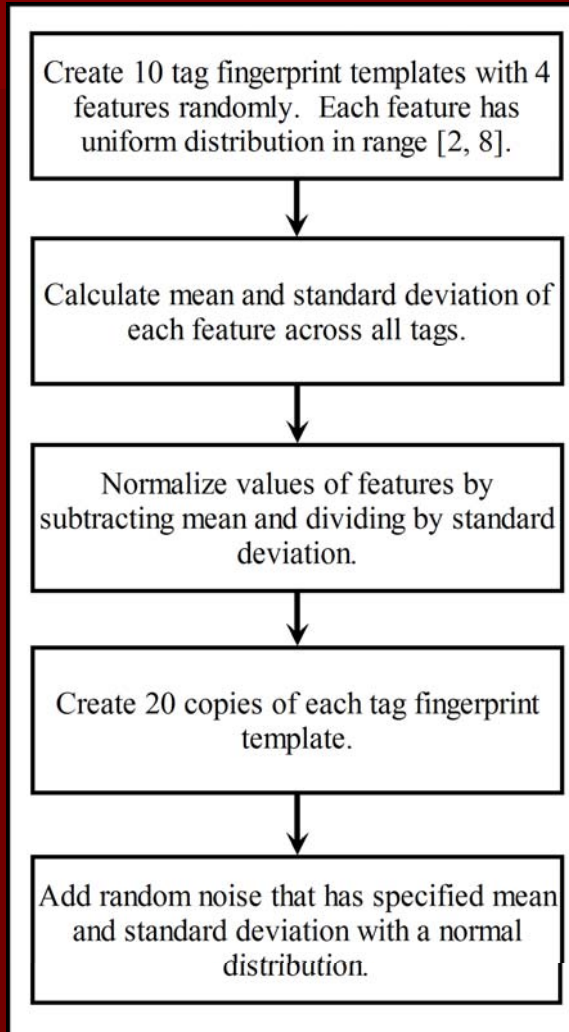
Hotelling's Two-sample T^2 Algorithm

$$T^2 = \frac{n_1 n_2}{n_1 + n_2} (\bar{y}_1 - \bar{y}_2)' S_{pl}^{-1} (\bar{y}_1 - \bar{y}_2)$$

$$S_{pl} = \left(\frac{1}{n_1 + n_2 - 2} \right) [(n_1 - 1)S_1 + (n_2 - 1)S_2]$$

$$\left[\frac{n_1 + n_2 - p - 1}{(n_1 + n_2 - 2)p} \right] T^2 = F_\alpha(p, n_1 + n_2 - p - 1)$$

Create synthetic tag fingerprints



Parameters

- $p = 4$ = number of features
- $n_1 = n_2 = 20$ = number of samples
- $\alpha = 0.025$ (95% confidence level)
- If $T^2 > 13.81$, assume fingerprints are different

$$T^2 > \left[\frac{(n_1 + n_2 - 2)p}{n_1 + n_2 - p - 1} \right] F_{\alpha}(p, n_1 + n_2 - p - 1)$$

Case 1: Compare fingerprint of tag 0 with all other fingerprints at varying noise levels (mean = 0)

Comparison of tag 0 with tag#	T ² for std. dev. 0.5	T ² for std. dev. 0.75	T ² for std. dev. 1.0	T ² for std. dev. 1.25	T ² for std. dev. 1.5
1	230.85	127.28	73.85	49.06	35.76
2	611.34	262.72	145.38	91.55	62.74
3	129.35	86.51	50.91	34.30	25.08
4	218.95	65.28	38.89	26.61	19.87
5	23.13	28.10	16.86	11.96	9.51
6	122.02	134.23	84.94	61.22	47.66
7	109.31	31.58	15.84	11.13	8.11
8	403.14	145.35	82.72	53.72	38.02
9	242.76	105.05	50.98	27.80	16.31

Table 6. Matching the fingerprint of tag 0 against other tag fingerprints with noise of mean 0 and standard deviation equal to 1.25.

Tag0 against Tag#	T^2 and σ = 1.25	$\left[\frac{(38)4}{35} \right] F_{\alpha=0.025}(4,35)$	Match
1	49.06	13.81	No
2	91.55	13.81	No
3	34.30	13.81	No
4	26.61	13.81	No
5	11.96	13.81	Yes
6	61.22	13.81	No
7	11.13	13.81	Yes
8	53.72	13.81	No
9	27.80	13.81	No

Table 8. FAR for noise levels with zero mean and five standard deviation values

Standard deviations, σ	False Acceptance Rate (FAR)
0.50	0%
0.75	0%
1.00	0%
1.25	22%
1.50	22%

Case 2: A single tag fingerprint with std. dev. 1.50 compared against itself at noise levels with different means

Noise level mean	T ² values for six different random fingerprints	$\left[\frac{(38)^4}{35} \right] F_{\alpha=0.025}(4,35)$	Average matching rate, %
0.25	2.00, 5.93, 3.27, 3.27, 4.92, 6.16	13.81	100
0.50	7.98, 12.61, 4.29, 8.77, 12.77, 7.96	13.81	100
0.75	17.97, 22.71, 7.29, 17.45, 25.11, 12.29	13.81	33
1.00	31.90, 36.25, 12.25, 29.29, 41.95, 19.17	13.81	17

Table 10. FRR of tag0's fingerprint against itself in noise levels with varying means and standard deviation 1.50 averaged over six runs.

Mean	False Rejection Rate (FRR)
0.25	0%
0.50	0%
0.75	67%
1.00	83%

Conclusions

- Hotelling's performs well across a large range of standard deviations IF the noise has zero mean
- Modest computations

Future Work

- Apply the algorithm to the measured features instead of the synthetic features
- Apply the algorithm across a much larger set of parameters

Contact Information

Dale R. Thompson, Ph.D., P.E.

Associate Professor

Computer Science and Computer Engineering Dept.

JBHT – CSCE 504

1 University of Arkansas

Fayetteville, Arkansas 72701-1201

Phone: +1 (479) 575-5090

FAX: +1 (479) 575-5339

E-mail: d.r.thompson@ieee.org

WWW: <http://comp.uark.edu/~drt/>